

Special Issue

Quality Control and Product Monitoring in Manufacturing

Message from the Guest Editors

Quality control and product monitoring play integral roles in modern manufacturing, ensuring consistent product quality, customer satisfaction, and regulatory adherence. This proposal outlines our intent to contribute to a special journal issue focused on these crucial aspects of manufacturing. Quality control encompasses systematic processes like statistical process control and Six Sigma methodologies. Product monitoring extends beyond the factory floor, involving real-time data collection and analysis using technologies such as IoT sensors, machine learning, and data analytics. These tools enable manufacturers to detect anomalies swiftly, improving product quality reducing waste and costs. In this Special Issue, we aim to explore recent advancements, best practices, and case studies in quality control and product monitoring across various manufacturing sectors. We will highlight how emerging technologies, data-driven insights, and collaborative strategies are reshaping these vital aspects of manufacturing, fostering innovation, sustainability, and global competitiveness.

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Message from the Editor-in-Chief

As the world of science becomes ever more specialized, researchers may lose themselves in the deep forest of the ever increasing number of subfields being created. This open access journal *Applied Sciences* has been started to link these subfields, so researchers can cut through the forest and see the surrounding, or quite distant fields and subfields to help develop his/her own research even further with the aid of this multi-dimensional network.

Editor-in-Chief

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